

Application No.	Applicant(s)
09/964,947	TSIAO ET AL.
Examiner	Art Unit
Matthew J Sked	2655

	SEAR	CHED	
	SEAR	CHED	
Class	Subclass	Date	Examiner
704	235	9/15	Ms
704	260	9/15	ans
704	257	9/15	MS
704	244	9/15	MS
704	275	9/15	1115
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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